

# Fundamental of HDD Technology (9)

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## Outline

- Read Process
  - Read Head
  - Noise and Disturbance
  - Read-Back Signal Model
  - Longitudinal and Perpendicular Pulses
- Read Channel Architecture

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## Read Process

- The read head converts magnetic flux to voltages.
  - Ferrite head  $\Rightarrow$  Good for the write process (bad for read)
  - Magneto-resistive (MR) head  $\Rightarrow$  Good for the read process because it is much more sensitive to changes in magnetic fields
  - Giant magneto-resistive (GMR) head  $\Rightarrow$  Introduced in 1997
  - Tunneling magneto-resistive (TMR) head  $\Rightarrow$  Recently used
- The better the heads, the higher the recording densities.
- Because of a variety of noises and disturbances in the read process, the read-back signal is distorted.

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## Read Process – Linear Superposition

- Unlike the write process, the read process is approximately linear.
- Linear superposition:

*“The readback voltage from a sequence of magnetic transitions is given by the sum of the single pulses corresponding to the individual magnetic transitions.”*

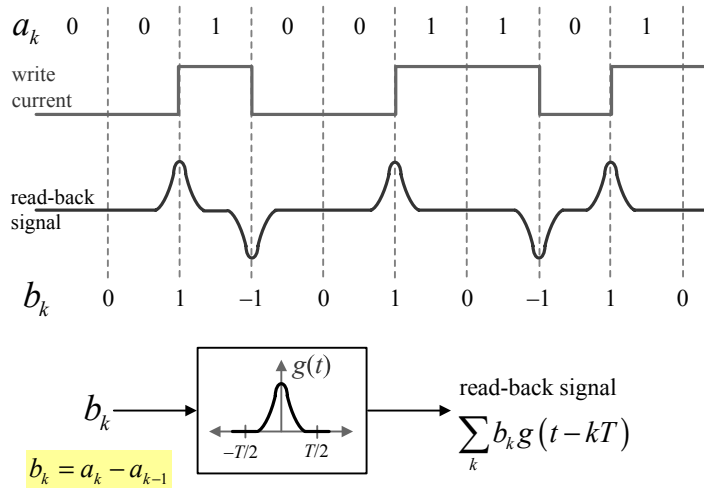
$$y(t) = \sum_k b_k g(t - kT)$$

$b_k$  = transition sequence  
 $g(t)$  = transition response

- Neighboring transition pulses will have opposite magnetic charge signs. Why?

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## Magnetic Medium Requirement

- **High coercivity**
  - To accommodate very sharp transition
- **High remanent magnetization but small thickness**
  - To provide large enough readback signal with minimum thickness space loss
- **Nearly squared hysteresis loop**
  - To achieve sharp transitions and satisfactory overwrite ratio
- **Very smooth surface and reliable mechanical stability**
  - To attain small magnetic spacing with acceptable tribological performance
- **Uniform, small and magnetically isolated magnetic grains**
  - To reduce medium noise in readback signals

## Noises

- The higher the recording densities, the more serious the noise.
- Noises are due to uncertainties in physical phenomena and need to be treated statistically.
- Three main sources:
  - Recording medium
  - Readback head
  - Preamplifier
- Usually, a magnetic recording system is designed to be medium noise limited.

## Other Disturbances

- **Interferences** are the reception or reproduction of signals other than those intended.
  - Deterministic
  - May be reduced to an arbitrarily small level by proper design
- **Nonlinear distortion** causes the linear superposition principle to fail.
  - Deterministic

## Medium Noise Mechanisms

- The **main source** of noises in magnetic recording systems is the magnetic recording medium itself.
- Medium noises are due to the fluctuations (or uncertainties) in the medium magnetization, which can be classified into three types:
  - Transition noise
  - Particulate or granularity noise
  - Modulation noise
- As ND  $\uparrow$   $\Rightarrow$  Transition noise  $\uparrow$   
Modulation noise  $\downarrow$   
Particulate noise (*independent*)

## Transition Noise

- Due to the magnetization fluctuation concentrated near the recorded transition centers.
- Dominant noise source in thin film disks.
- **Nonstationary**  $\Rightarrow$  this noise depends on recording patterns (i.e., data dependence)

## Particulate or Granularity Noise

- Due to the random dispersion of magnetic particles or grains in magnetic medium.
- Dominant noise source in magnetic tapes, floppy disks, and particulate thin film hard disks.
- **Stationary**  $\Rightarrow$  the noise is independent of the location along the data track.

## Modulation Noise

- Due to the magnetization fluctuation proportional to recorded magnetization between magnetic transitions (non-transition areas).
- Observed in both particulate and continuous thin-film disks.
- **Nonstationary**

## Head and Electronics Noises

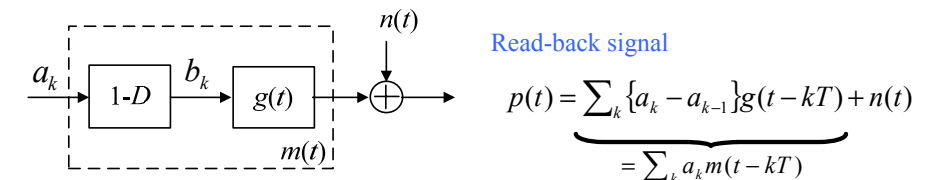
- **Head noise** arises from fluctuations of magnetic domain walls of the head core material (Barkhausen noise), or from the resistive dissipation in the head (Johnson noise).
- **Electronics noise** is caused by the random fluctuations in time of the electric carriers.
  - Mainly generated by the preamplifier (the first stage amplifier) in data-detection circuitry.
  - **Shot noise** and **thermal noise** usually dominates electronics noise in magnetic recording, which are more or less white noise.

## Noises, Distortions, and Interference in Magnetic Recording

<b>Noises</b>	<b>Medium noises</b>  <b>Head noises</b>  <b>Electronics noises</b>	Transition noise Particulate noise Modulation noise Johnson noise Barkhausen noise Shot noise Johnson noise Flicker noise
<b>Distortions</b>	<b>Write distortions</b>  <b>Read distortions</b>	Nonlinear transition shift Hard transition shift Partial erasure AMR head nonlinearity GMR head nonlinearity
<b>Interferences</b>	<b>On-track</b>  <b>Off-track</b>	Linear transition shift Residual old information Side read, track edge effect Head position misregistration

- Thermal noise  $\Rightarrow$  from the read head and pre-amp
- Background noise  $\Rightarrow$  from the media
  - Due to the slight misalignment of magnetic grain axes
- Offtrack noise:
  - From the “erase band” region (similar to background noise), or
  - Due to transitions on an adjacent track
- Transition noise  $\Rightarrow$  mainly from thin-film media
  - Uncertainties in the position of a transition
  - Deviations in the shape of a transition
  - Changes in the length of a transition
- Most noise sources are statistically independent of the signal, except the transition noise, which only occurs when the signal contains transitions.

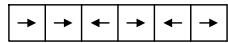
## Model for Generating a Read-Back Signal



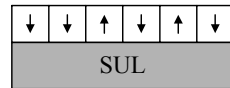
- where  $a_k \in \{\pm 1\}$  = data bit  
 $D$  = delay operator  
 $b_k = a_k - a_{k-1} \in \{0, \pm 2\}$  = transition bit  
 $g(t)$  = transition response  
 $m(t) = g(t) - g(t-T)$  = dibit response (or symbol response)  
 $T$  = bit period  
 $n(t)$  = additive white Gaussian noise (AWGN)

# Longitudinal vs. Perpendicular

## Orientation:



Longitudinal recording

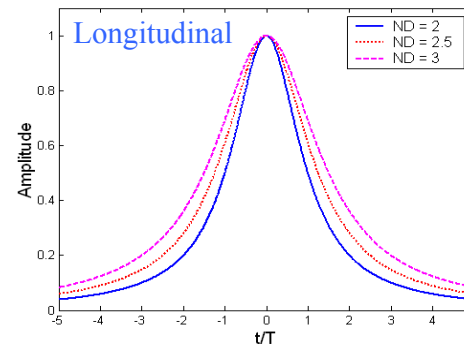


Perpendicular recording

## Design issues:

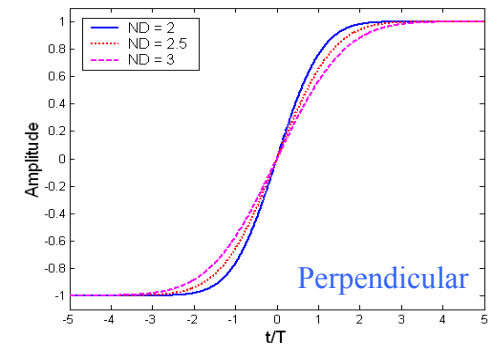
- Magnetic medium
- Read/write head
- Signal Processing
  - Target  $\Rightarrow$  PR or GPR
  - Dominant error sequence  $\Rightarrow$  longitudinal  $\{-, +, -\}$   
perpendicular  $\{-, +\}$

# Transition Response: $g(t)$



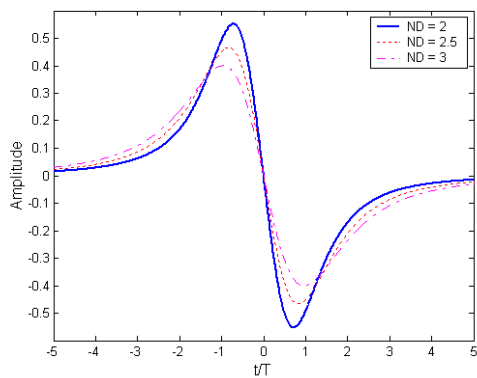
$$g_L(t) = \frac{1}{1 + (2t / PW_{50})^2}$$

- $ND = PW_{50}/T$  is a **normalized recording density**.
- $PW_{50}$  is the width of  $g_L(t)$  or  $g'_p(t)$  at half of its peak value.

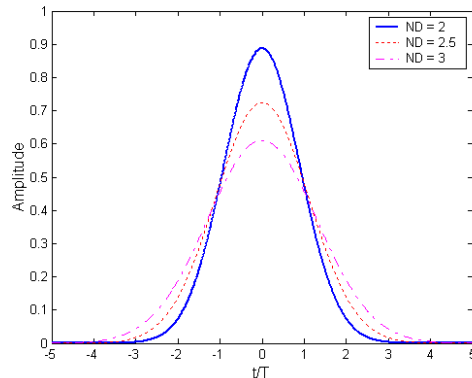


$$g_p(t) = \text{erf}\left(\frac{2t\sqrt{\ln 2}}{PW_{50}}\right)$$

# Dibit Response: $m(t) = g(t) - g(t-T)$

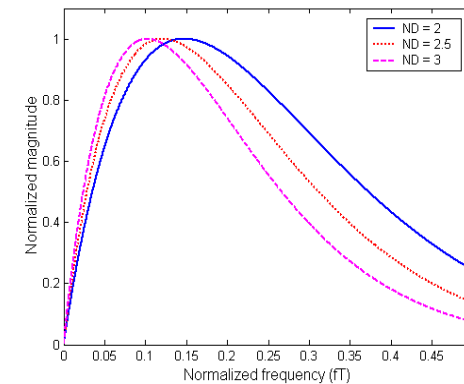


Longitudinal



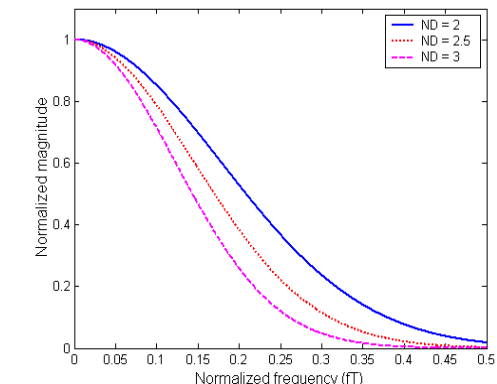
Perpendicular

# Frequency Response (of Dibit Response)



Longitudinal

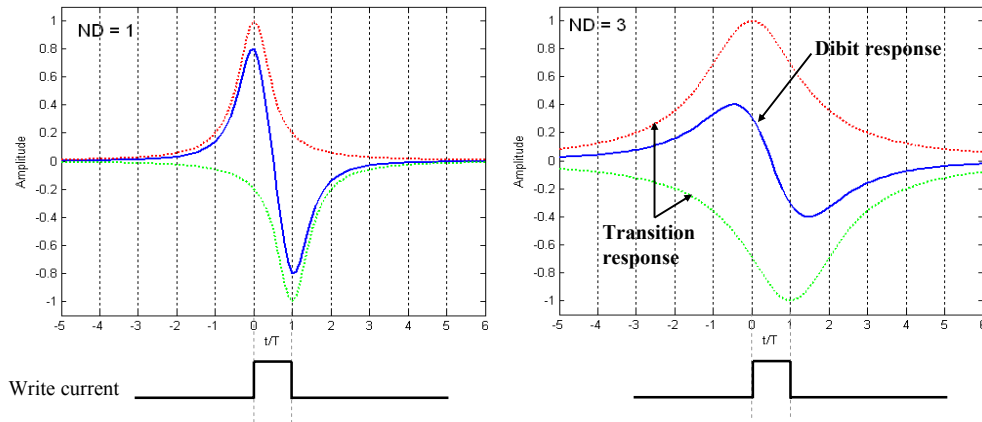
$$M_L(f) = \exp\left[-\pi|f|PW_{50}\right] \cdot (1 - e^{-j2\pi fT})$$



Perpendicular

$$M_P(f) = \frac{1}{j\pi f} \cdot \exp\left\{-\frac{\pi^2 f^2 PW_{50}^2}{\ln 16}\right\} \cdot (1 - e^{-j2\pi fT})$$

## Linear Combination of Two Adjacent Transitions

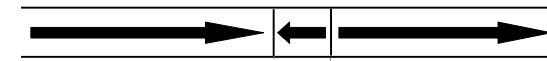


**Observe**  $\Rightarrow$  ND increases  $\Rightarrow$  signal amplitude is reduced, and peak is shifted.

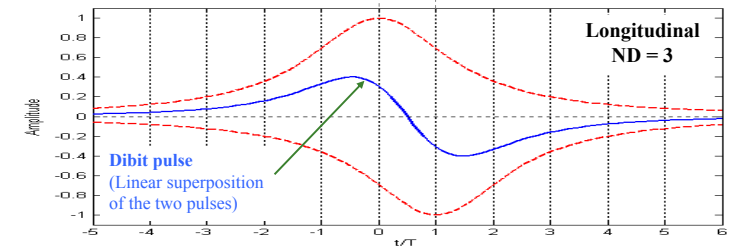
- This results in a symbol response or a dibit response.

## Effects of ISI

Media

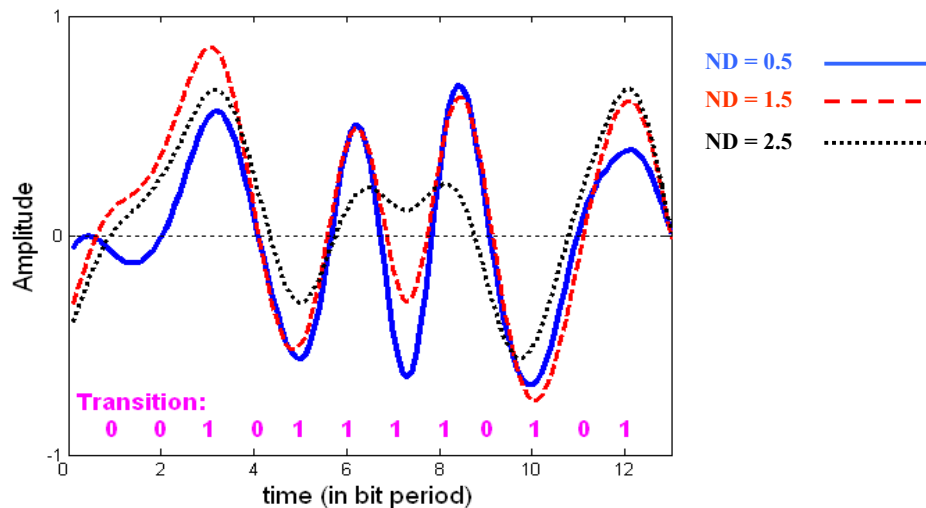


Read-back signal



- Reduce pulse amplitude
- Move peaks apart
- Is #1 source of error in peak detection (the higher the ND, the more severe the ISI).

## Example of Read-Back Signals (@ SNR = 20 dB)



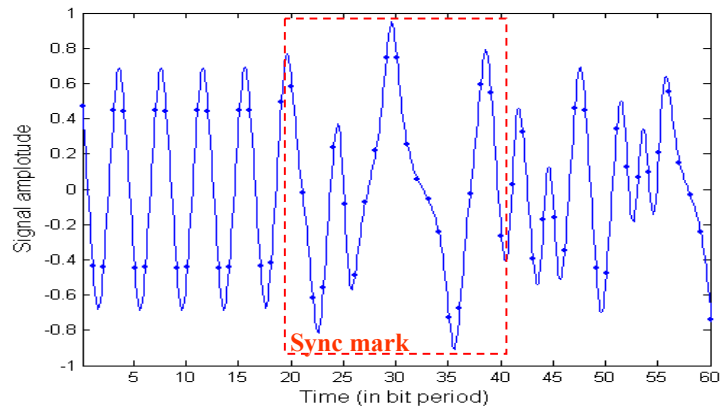
## Ways to Handle ISI

- Prevent it by
  - Precompensation
  - Pulse slimming (read-channel equalization)
  - RLL codes
- Encounter and attack it by
  - Partial response maximum-likelihood (PRML) technique

## Example of Read-Back Signals (no noise)



Preamble is constant frequency  
Sync mark is a fixed pattern  
Data bits are normally random

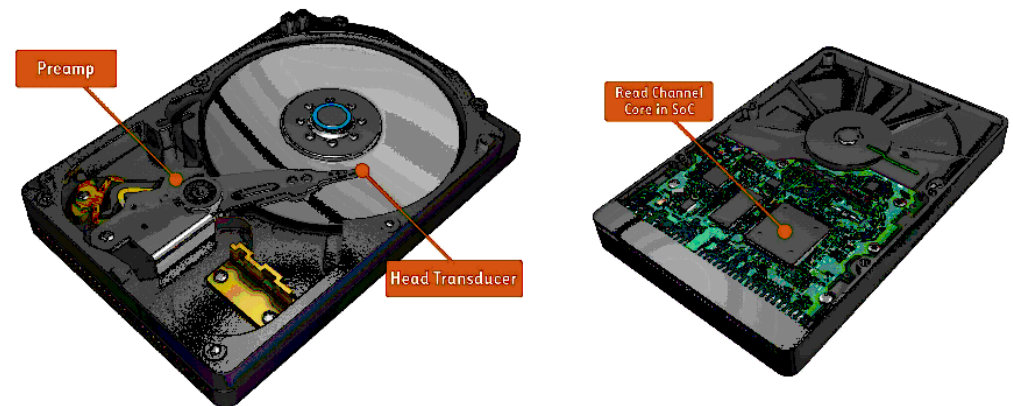


## Read Channel Architecture

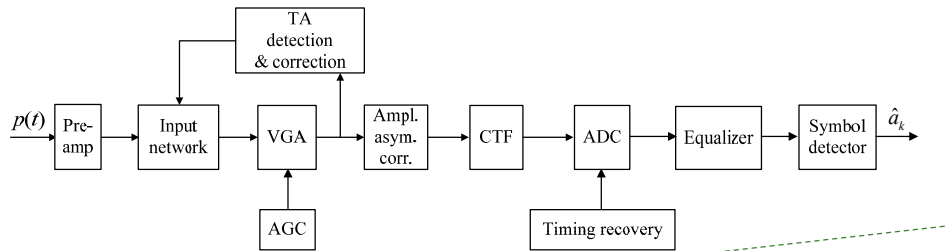
- Pre-Amp
- Variable Gain Control
- Thermal Asperity
- Amplitude Asymmetry
- Continuous-Time Filter
- Analog-to-Digital Converter
- Timing Recovery
- Equalizer
- Symbol Detector

## Read Channel

- The read-channel integrated circuit (IC) is **an electronic heart of HDDs**.
- Over the years, read-channel designers have delivered dramatic improvement in SNR, enabling accurate, reliable recovery of user data from noisy analog signal.
- Hard disk designers have taken advantage of SNR improvements to make data tracks on a storage disk smaller and pack those tracks tighter.
- Today's areal density  $\Rightarrow$  > 150 GB/platter (3.5")  
> 80 GB/platter (2.5")



# Read Channel Architecture



**Notation:**

TA = Thermal Asperity

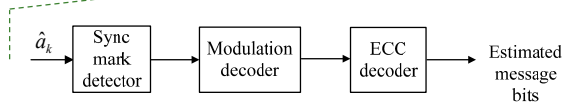
VGA = Variable Gain Amplifier

AGC = Automatic Gain Control

Ampl. asym. corr. = Amplitude Asymmetry Correction

CTF = Continuous-Time Filter (or a low-pass filter)

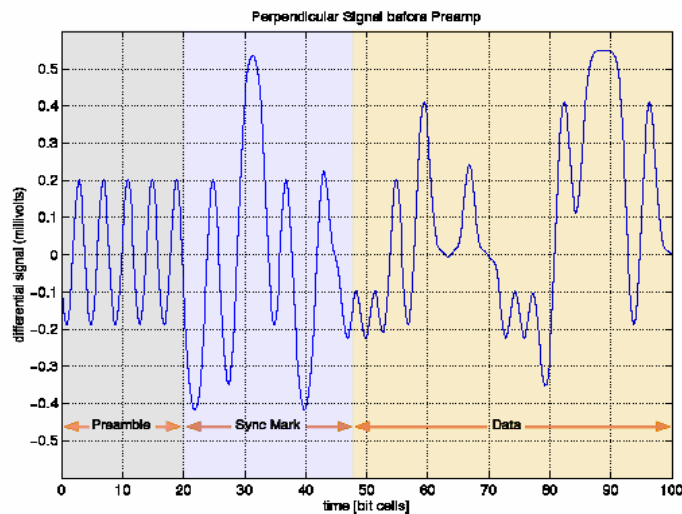
ADC = Analog-to-Digital Converter



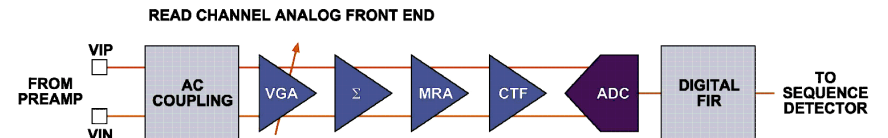
# Pre-Amp

- The head signal is very small.
  - As small as 300 microvolts peak-to-peak
- Pre-amp:
  - To amplify the head signal to significantly higher amplitude to meet the tens of millivolts required to preserve the SNR level capability of the head signal and maximize the read-channel's capabilities once it arrives at the channel.

# Ideal perpendicular magnetic signal output from the head transducer before the preamp



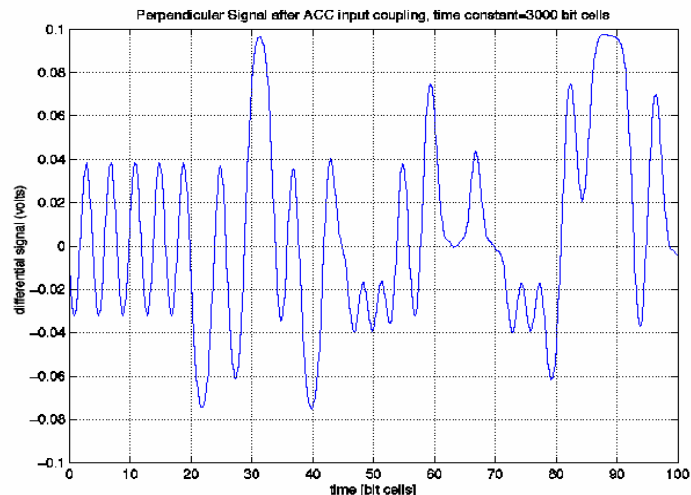
# AC Coupling



- The first stage of the analog front end of the channel core consists of a stage to **remove DC offset** in the signal.
- This is accomplished through AC coupling and DC baseline correction.



Perpendicular signal after AC coupling still showing some DC offset of positive versus negative peaks in the preamble.



## Variable Gain Amplifier (VGA)

- To provide gain determined by the **automatic gain control (AGC)**.
- To control the signal level for optimum performance in the analog-to-digital converter (ADC) block.
- **Note:**
  - **Too much** gain can cause the ADC sample values to rail at maximum or minimum ADC levels.
  - **Too little** gain can cause quantization noise to dominate SNR and adversely affect bit-error rate performance.

## Automatic Gain Control (AGC)

- In practice, the read-back signal levels may **vary widely**.
- The **AGC** is used to make the signal levels behind the VGA are more or less constant.
  - AGC is typically an analog circuit.
- **Category:**
  - Non-data-aided AGC
  - Data-aided AGC

## Summing Junction $\Sigma$

- Add in any additional DC correction necessary beyond the DC attenuation provided in the AC coupling stage.
- Keep the signal centered on the baseline which will become mid scale for the ADC converter
  - So that the sequence detector trellises will work optimally
- So correction reduces the preamble offset, thus producing a more centered signal.

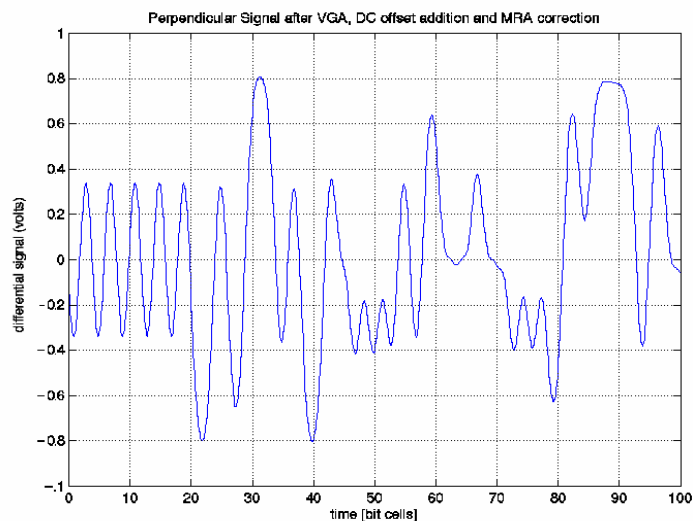
## Amplitude Asymmetry

- The use of the MR read head can result in positive-negative peak “**asymmetry**” in the data signal at the output of the read head [Tsang *et al*, 1990].
  - The magnitude of the response due to a positive magnetic transition differs from that of a negative magnetic transition.
  - In the absence of asymmetry, the read-back signal can be viewed as the linear combination of transmitted pulses.
- Positive-negative peak asymmetry is an approximation for nonlinear behavior that occurs when a biased MR head slightly saturates in one direction.
- This asymmetry causes many errors in data detection process.

## Amplitude Asymmetry Correction

- **Reconstruct linearity** that may have been lost in the head transducer stage during the conversion of the magnetic signal on the disk to an electrical signal at the output of the head
- The biasing of the head signal is adjusted to keep the signal in the linear range of the head sensitivity curve.
- Use signal offset to determine the amount of squared signal to add back to restore the positive and negative symmetry of the signal

### Perpendicular signal after DC offset and MRA correction



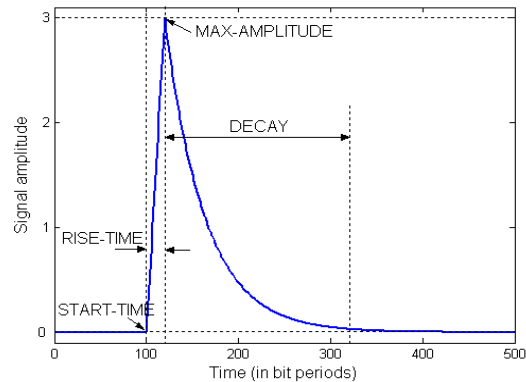
## Thermal Asperity (TA)

- When an **asperity** (or a **surface roughness**) comes into contact with the slider, both the surface of the slider and the tip of the asperity are heated, which results in an extra voltage transient known as **thermal asperity (TA)**.
- TA causes a major problem in magnetic recording systems.
  - Loss of synchronization
  - Off-track perturbation
- Without TA detection and correction algorithms [Erden and Kurtas, 2004], the system performance can be unacceptable, depending on how severe the TA effect is.

## Modeling the TA Signal

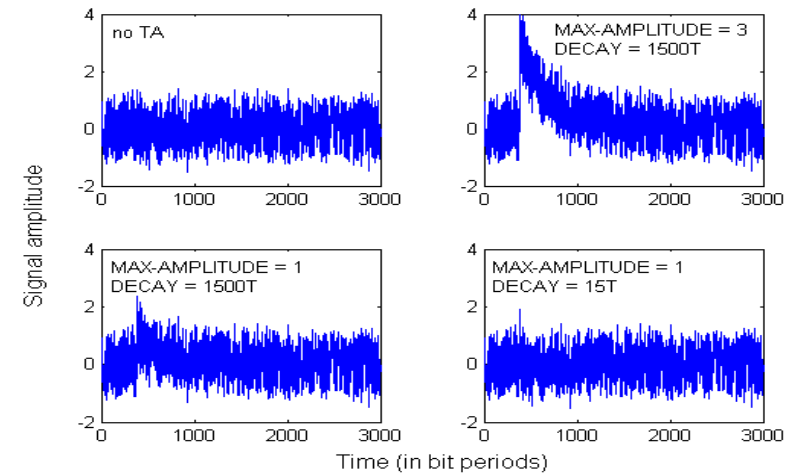
- The widely used TA model\* [Stupp *et al*, 1999] is specified by four parameters:

- START TIME
- RISE TIME
- MAX AMPLITUDE
- DECAY CONSTANT

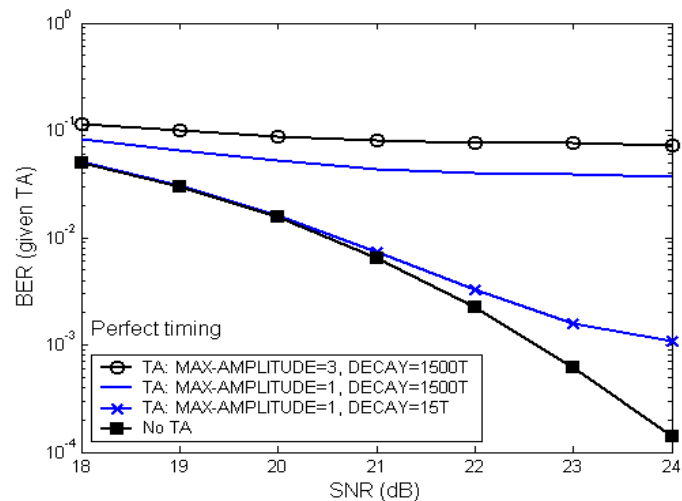


\* Because it fits captured spin stand data and drive data very well.

## Read-Back Signals with TA



## Example: System Performance with TA



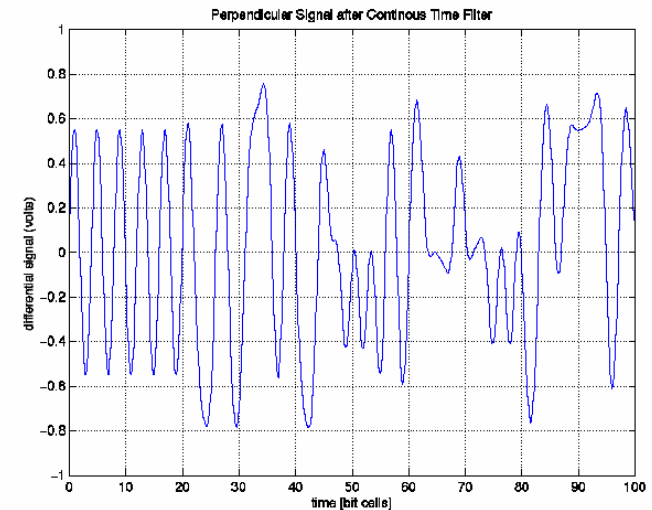
## Continuous-Time Filter (CTF)

- CTF  $\Rightarrow$  7th-order equi-ripple **lowpass filter**
- To provide mid-band peaking to help with achieving the target signal response.
- To keep the signal energy below the Nyquist rate to minimize any aliases that may occur when the analog signal is converted to a sampled representation
- To eliminate the out-of-band noise.

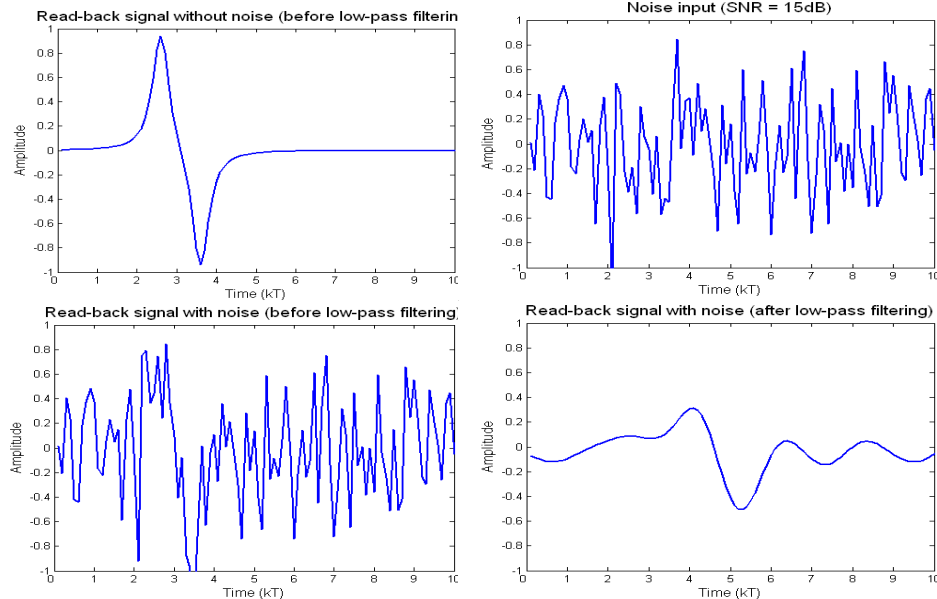
## Booster in CTF

- Closely spaced multiple transitions result in high frequency energy in the signal, which is attenuated by the lowpass nature of the read process [Uehara and Gray, 1994].
- Boosting high frequency energy in the signal is useful in shaping the signal to meet the digital target signal characteristics.

## Perpendicular signal after CTF low pass filter



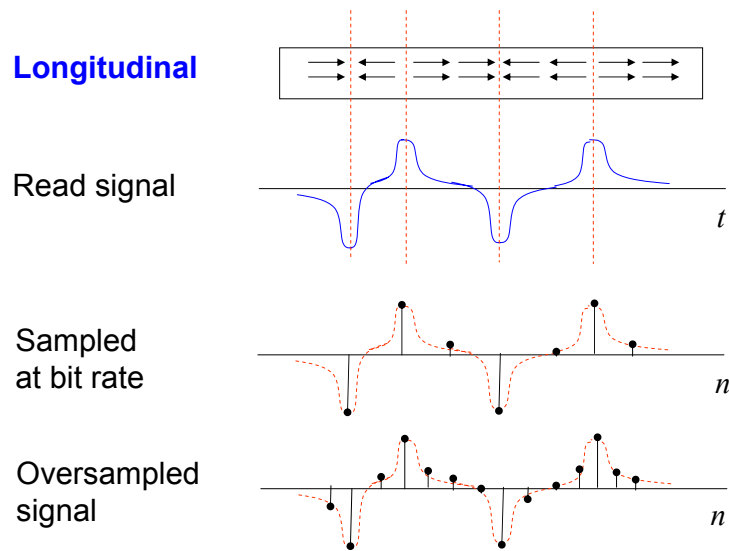
## Signal Response @ Long, $ND = 0.5$ , $SNR = 15$ dB



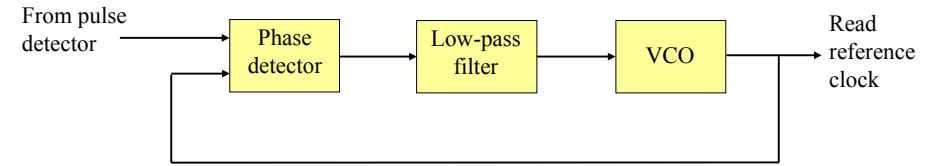
## Analog-to-Digital Converter (ADC)

- Used to convert an analog signal to a digital samples, quantized in time and amplitude.
- Controlled by a **timing recovery** block.
- Currently, a **6-bit** ADC is employed in HDD.
  - More bits  $\Rightarrow$  low quantization noise, high complexity, expensive
  - Less bits  $\Rightarrow$  high quantization noise, low complexity, cheap
- Sampling rate:
  - Symbol-rate sampling
  - Oversampling
    - Give more samples per one clock period  $\Rightarrow$  more information for timing recovery
    - Expensive for implementation

## Longitudinal

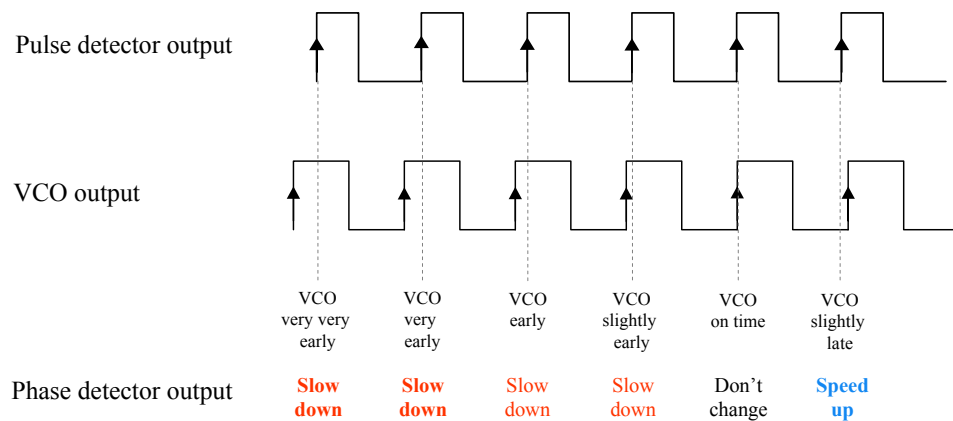


## Phase Locked-Loop (PLL)



- **Phase detector:** Compare the input pulse with the clock pulse
  - If the clock is **later** than the input  $\Rightarrow$  **speed up** the VCO
  - If the clock is **earlier** than the input  $\Rightarrow$  **slow down** the VCO
- **Low-pass filter:** Average the signal from the phase detector to reduce the effect of noise.
- **Voltage-controlled oscillator (VCO):** Generate a clock with the frequency determined by the voltage of the input.

## Example: PLL Operation



Sampled signal after ADC, analog to digital converter

